



# Computer Vision Research Areas

- Commonly broken down according to degree of abstraction from image
  - Low-level: mapping from pixels to pixels
    Edge detection, feature detection, stereopsis, optical flow
  - Mid-level: mapping from pixels to regions
    Segmentation, recovering 3d structure from motion
  - High-level: mapping from pixels and regions to abstract categories
  - Recognition, classification, localization

### **Today's Overview**

- Focus on some mid- and high-level vision problems and techniques
- Illustrate some computer vision algorithms and applications
- Segmentation and recognition because of potential utility for analyzing images gathered in the laboratory or the field
  - Cover basic techniques rather than particular applications
- Cornell Unive





## Graph Based Formulation

• *G*=(*V*,*E*) with vertices corresponding to pixels and edges connecting neighboring pixels



4-connected or 8-conneted

- Weight of edge is magnitude of intensity difference between connected pixels
- A segmentation, S, is a partition of V such that each C∈S is connected

Cornell University

























- For costs, natural to consider minimum cost cuts
  - Removing edges with smallest total cost, that cut graph in two parts
  - Graph only has non-infinite-weight edges
- For segmentation, recursively cut resulting components
  - Question of when to stop
- Problem is that cuts tend to split off small components

Cornell University











### Segmentation

#### Many other methods

- Graph-based techniques such as the ones illustrated here have been most widely used and successful
- Techniques based on Markov Random Field (MRF) models have underlying statistical model
  - Relatively widespread use for medical image segmentation problems
- Perhaps most widely used non-graph-based method is simple local iterative update procedure called Mean Shift

Cornell University

#### **Some Segmentation References**

- J. Shi and J. Malik, "Normalized Cuts and Image Segmentation," *IEEE Transactions on Pattern Analysis and Machine Intelligence*, vol. 22, no. 8, pp. 888-905, 2000.
- P. Felzenszwalb and D. Huttenlocher, "Efficient Graph Based Image Segmentation," *International Journal of Computer Vision*, vol. 59, no. 2, pp. 167-181, 2004.
- D. Comaniciu and P. Meer, "Mean shift: a robust approach toward feature space analysis," *IEEE Transactions on Pattern Analysis and Machine Intelligence*, vol. 24, no. 4, pp. 603-619, 2002.

Cornell Univer





















## Using Appearance and Geometry

- Constellations of parts [FPZ03]
  - Detect affine-invariant features
     E.g., corners without preserving angle
  - Use Gaussian spatial model of how feature locations vary within category (n x n covariance)
  - Match the detected features to spatial model





















## Learning the Models

- [FPZ05] uses feature detection to learn models under weakly supervised regime
  - Know only which training images contain instances of the class, no location information
- [CFH05] does not use feature detection but requires extensive supervision
  - Know locations of all the parts in all the positive training images
- Investigate weak supervision but without relying on feature detection

Cornell University

#### Weakly Supervised Learning

- Consider large number of initial patch models to generate possible parts
- Generate all pairwise models formed by two initial patches – compute likelihoods
- Consider all sets of reference parts for fixed k
- Greedily add parts based on likelihood to produce initial model
- EM-style hill climbing to improve model

Cornell Univers





## Some Recognition References

- D.P. Huttenlocher, G.A. Klanderman, W.A. Rucklidge, "Comparing Images Using the Hausdorff Distance," *IEEE Transactions on Pattern Analysis and Machine Intelligence*, vol. 15, no. 9, pp. 850-863, 1993.
- D.G. Lowe, "Object recognition from local scale-invariant features," *IEEE Conference on Computer Vision and Pattern Recognition*, pp. 1150-1157, 1999.
- D. Crandall, P. Felzenszwalb and D. Huttenlocher, "Spatial priors for part-based recognition using statistical models," *IEEE Conference on Computer Vision and Pattenr Recognition*, pp. 10-17, 2005.

53